SHEET 1 OF 1

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Form PTO 1449		U.S. DEPARTMENT	OF COMMERCE	ATTY DOCKET NO.	2 MAY TO ST	[4]	SERIAL I	NO.	
(Modified)		U.S. DEPARTMENT PATENT AND TRAI	EMARK OFFICE	246070US2	A STATE OF THE STA	<i>\$</i> }/	10/722,	,602	
				APPLICANT	PARABEMA	"	*		
LIST OF	REFER	RENCES CITED BY AP	PLICANT	Kouji MITSUHAS	SHI, et al.				
				FILING DATE			GROUP	· · · · · ·	
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EXAMINER INITIAL	<u> </u>	DOCUMENT NUMBER	DATE	NAM			SUB FILING DAT CLASS IF APPROPRI		
RD	AA	5,952,054	9-14-99	Sato et al.					
	АВ								
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			FO	REIGN PATENT DOC	UMENTS				
		DOCUMENT	DATE	C	OUNTRY			TRANSLAT	TION
		NUMBER	DAIL				YE	S	NO
RD	AO	1999-008142	1-25-99	Korea (Corresponds					×
	AP	05-070922	3-23-93	Japan (English Abstr translation)					
	AQ	2001-152307	6-5-01	Japan (English Abstr translation)					
	AŖ	10-130884	5-19-98	Japan (English Abstr translation)	act w/partial comp	uterized			
	AS								
	AT						 		
	AU		<u> </u>						
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		OTHER RI	EFERENCES (Including Author, Tit	le, Date, Pertinent	Pages, e	tc.)		
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	AY								
	AZ					Add	itional Refe	erences she	et(s) attached
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*Examiner: Ir	nitial if r	eference is considered,	whether or no	t citation is in conforma	ance with MPEP 60	9; Draw li	ne through	citation if n	ot in
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Form PTO 1449 U.S. DEPARTMENT OF			RTMENT OF	ATTY DOCKET NO.	SERIAL NO.		
COMMERCE (Modified)		PATENT A	AND TRADEMARK	246070US2	10/722,602		
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LIST OF RE	FERE	NCES CITED BY	APPLICANT	Kouji Mitsuhashi, et al.			
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			NO 5 3000	OREIGN PATENT DOCUMENTS			
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INITIAL		DOCUMBNE NUMBER	TA PARTY	COUNTRY	YES	NO	
RD	AA	1 156 130	11/21/2001	Europe (in English)			
i i	AB	10-004083	01/06/1998	Japan (w/ English abstract and computer translation)	×		
	AC	2001-226773	08/21/2001	Japan (w/ English abstract; corresponding to US 2001/0003271 A1)	1	×	
	AD	2000-303180	10/31/2000	Japan (w/ English abstract; corresponding to US 2003/0010446 A1)		×	
	AE	0 814 495	06/1997	Europe (in English)			
	AF	05-198532	08/1993	Japan (w/ English abstract and computer translation)	x		
	AG	10-214819	08/1998	Japan (w/ English abstract and computer translation)	x		
	АН	2002-151473	05/2002	Japan (w/ English abstract; corresponding to US 2004/0035364 A1)		×	
	Al	02/39495	05/16/2002	WIPO (w/ English abstract; corresponding to US 2004/0035364 A1)		×	
	ĀJ	1 069 603	01/17/2001	Europe (in English)			
	AK	07-245295	09/1995	Japan (w/ English abstract and computer translation)	x		
	AL	0 841 838	05/1998	Europe (in English)			
	AM	99/50886	10/1999	WIPO (in English)			
_	AN	0 573 057	12/1993	Europe (in English)			
	AO	2000-124197	04/28/2000	Japan (w/ English abstract and computer translation)	x		
	AP	1 081 749	07/03/2001	Europe (in English)			
	AQ	4-238882	08/1992	Japan (w/ certified English translation)	x	·	
	AR	1-312087	12/1989	Japan (w/ English abstract; corresponding to US Patent 4,968,374)		×	
	AS	08-041309	02/1996	Japan (w/ English abstract and computer translation)	x		
	AT	08-081777	03/26/1996	Japan (w/ English abstract and computer translation)	×		
	AU	08-268751	10/15/1996	Japan (w/ English abstract and computer translation)	x		
	ΑV	07-226378	08/22/1995	Japan (w/ English abstract and computer translation)	x		
	AW	64-039728	02/1989	Japan (w/ certified English translation)	x		
	AX	03-115535	05/1991	Japan (w/ certified English translation)	x		
	AY	05-117064	05/1993	Japan (w/ English abstract and corresponding to EP 0 508 731 filed herewith)		×	
	AZ	05-238859	09/1993	Japan (w/ English abstract and computer translation)	×		
	ВА		03/1994	Japan (w/ English abstract and computer translation)	×		
	ВВ	06-136505	05/1994	Japan (w/ English abstract and computer translation)	×	<u> </u>	
	вс		05/1994	Japan (w/ English abstract and computer translation)	×		
	BD		05/1995	Japan (w/ English abstract and computer translation)	×		
	BE		07/1995	Japan (w/ English abstract and computer translation)	×		
	BF	08-037180	02/1996	Japan (w/ English abstract and computer translation)			
	BG	08-339895	12/1996	Japan (w/ English abstract; corresponding to US Patent 5,919,332)		×	
	вн	09-069554	03/1997	Japan (w/ English abstract; corresponding to US Patent 5,909,354)		х	
	BI	09-272987	10/1997	Japan (w/ English abstract; corresponding to US Patent 5,955,182)		x	
				Additional References sheet(s)	attached		
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Examiner		/Ra	kesh Dhing:	Date Considered 08/	08/2006		
				r or not citation is in conformance with MPEP 609; Draw line through citation	if not in		
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Form PTO 14 COMMERCE	49	U.S. DEPA	RTMENT OF	ATTY DOCKET NO.	SERIAL				
(Modified) OFFICE		PATENT /	ND TRADEMARK	246070US2 10/722,6					
			ADDLICANT	APPLICANT					
LIST OF	REFERE	NCES CITED BY	APPLICANT	Kouji Mitsuhashi, et al.	GROUP				
				November 28, 2003	1763				
	 .			FOREIGN PATENT DOCUMENTS	1				
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EXAMINE INITIAL	R	DOCUMENT NUMBER	DATE	COUNTRY	YES	NO			
RD	AA	10-045461	02/1998	Japan (w/ English abstract and computer translation)	×	ļ			
	AB	10-045467	02/1998	Japan (w/ English abstract and computer translation)	×				
	AC	11-080925	03/1999	Japan (w/ English abstract; corresponding to US Patent 6,139,983)		x			
	AD	11-207161	08/1999	Japan (w/ English abstract and computer translation)	×				
	AE	2001-031484	02/2001	Japan (w/ English abstract and computer translation)	×				
	AF	10-251871	09/1998	Japan (w/ English abstract; corresponding to US Patent 6,120,640)		×			
	AG	02/48421	06/20/2002	WIPO (w/ English abstract; corresponding US 2004/0081746 A1)		×			
	AH	01/42526	06/14/2001	WIPO (w/ English abstract; corresponding to US Patent 6,783,863)		×			
	Al	0 508 731	10/14/1992	Europe (in English)					
	AJ	2001-164354	06/19/2001	Japan (w/ computer translation; English abstract; corresponding to US Patent 6,783,863)	х.				
	AK	11-233292	08/27/1999	Japan (w/ English abstract and computer translation)	×				
	AL	11-312646	11/09/1999	Japan (w/ English abstract; corresponding to US Patent 6,383,333)		х			
	AM	05-121360	05/18/1993	Japan (w/ English abstract and computer translation)	×				
	AN	94 21 671	07/1996	Germany (w/ computer translation)	×				
	AO	2 252 567	08/1992	Great Britain					
	AP	06-256926	09/1994	Japan (w/ English abstract and computer translation)	×				
	AQ	0 799 904	10/1997	Europe (in English)					
	AR	61-207566	09/1986	Japan (corresponding to US 5,204,189)					
	AS	07-058013 A	03/1995	Japan (English abstract and computer translation)	×				
	AT	02-267967	11/1990	Japan (Certified translation filed herewith)	×				
	AU	2004/030011	04/2004	WIPO					
	AV	2004/030012	04/2004	WIPO					
	AW	2004/030013	04/2004	WIPO					
	AX	2004/030014	04/2004	WIPO					
	AY	2004/030015	04/2004	WIPO					
	AZ	2004/030020	04/2004	WIPO					
	ВА	2004/030426	04/2004	WIPO					
	ВВ	2004/095530	11/2004	WIPO					
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Examiner	_L	/Rakesh	Dhingra/	Date Considered 08/08	/2006				
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Form PTO 1449 COMMERCE		U.S. DEPAR		ATTY DOCKET NO.	SERIAL NO.		
(Modified) OFFICE		PATENT AN	ND TRADEMARK	246070US2	10/722,602	· · · · · · · · · · · · · · · · · · ·	
3 132				APPLICANT			
LIST OF REF	ERE	NCES CITED BY	APPLICANT	Kouji Mitsuhashi, et al.	·		
				FILING DATE	GROUP		
				November 28, 2003	1763		
			U.S. P.	ATENT DOCUMENTS			
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME		CLASS	SUB CLASS
RD	AA	6,176,969	01/23/2001	Park et al.			ļ
	AB	5,919,332	07/06/1999	Koshiishi et al.			
	AC	2004/0035364	02/26/2004	Tomoyoshi et al.			
	AD	5,366,585	11-1994	Robertson et al.			
	AE	5,868,848	02-1999	Tsukamoto, Yuji		<u> </u>	
	AF	6,110,287	08-2000	Arai et al.			
	AG	6,129,808	10-2000	Wicker et al.			
-	АН	6,264,788	07-2001	Tomoyasu et al.			
	Al	6,394,026	05-2002	Wicker et al.			
	AJ	6,444,083	09-2002	Steger et al.			
	AK	6,514,377	02-2003	Morimoto, Tamotsu			
	AL	6,527,911	03-2003	Yen et al.			
	AM	6,533,910	03-2003	O'Donnell et al.			
	AN	6,537,429	03-2003	O'Donnell et al.		T	
	AO	6,544,380	04-2003	Tomoyasu et al.			
	AP	6,583,064	06-2003	Wicker et al.			
	AQ	6,733,620	05-2001	Sugiyama et al.			
	AR	2002/0086501	07-2002	O'Donneil et al.			
	AS	2002/0086545	07-2002	O'Donneli et al.			
1 1	AT	2002/0086553	07-2002	O'Donnell et al.			
	AU	2002/0142611	10-2002	O'Donnell et al.			
	AV	2003/0084848	05-2003	Long, Maolin			
	AW		02-2004	Takenaka et al.			
	AX	2004/0060516	04-2004	Nishimoto et al.			
	AY		04-2004	Saigusa et al.			
	AZ	2004/0060657	04-2004	Saigusa et al.			
	ВА		04-2004	Nishimoto et al.			
	ВВ		04-2004	Nishimoto et al.			
	ВС		04-2004	Salgusa et al.			
	BD		04-2004	Saigusa et al.			
	BE		07-2004	Ludviksson et al.			
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(Modified)		PATENT AND TRAD	EMARK OFFICE	246070US2 10/722,602			602	
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LIST OF	REFE	RENCES CITED BY API	PLICANT	Kouji Mitsuhashi, et al.				
				FILING DATE		GROUP		
				November 28, 2003		1763		
			U.S	. PATENT DOCUMENTS				
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE	
RD	AA	6,894,769	05/2005	Ludviksson et al.				
ı	AB	6,875,477	04/2005	Trickett et al.				
	AC	6,852,433	02/2005	Maeda, Takao				
	AD	6,833,279	12/2004	Choi, Jin-Sik		_		
	AE	6,811,651	11/2004	Long, Maolin				
	AF	6,806,949	10/2004	Ludviksson et al.				
	AG	6,805,952	10/2004	Chang et al.				
	AH	6,783,875	08/2004	Yamada et al.				
	Al		08/2004	Sun et al.				
	ĀĴ		09/2003	O'Donnell et al.			-	
	AK	4,877,757	10/1989	York et al.				
	AL		06/1997	Oehrlein et al.				
	AM	5,834,070	11/1998	Movchan et al.		i		
	AN	6,296,740	10/2001	Xie et al.		Ì		
	AO		09/2003	Xie et al.				
	AP	-,,	04/1999	Wong et al.				
	AQ	3,000,000	03/2004	Sumiya et al.				
	AR		05/2004	Imafuku et al.				
	AS		03/1999	Zhao et al.				
	AT		12/2001	Nishikawa et al.				
	AU		05/1999	Waku et al.				
	AV	· / · · · · · · · · · · · · · · · · · ·	06/1995	Tomita et al.				
	AW	-,,	04/2003	Kuibira, et al.				
	AX	-,,	07/2001	Miyajima, et al.				
	AY	0,200,133	07/2001	wayajima, et al.				
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RD	AZ	Production drawing	for Deposit	ion Shield, Upper believed to be	sold in t	he U.S. o	on April 12, 2000.	
		Production drawing 2001.	for Deposit	ion Shield believed to be sold in	the U.S.	prior to	September 30,	
	вв			Electrode believed to be sold in the				
		JIS Using Series, "S Association), with E		chniques Manual.", p. 95 (Oct. 3) slation	0, 1998,	Japanes	e Standard	
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Form PTO 1449	U.S. DEPARTMENT OF COMMERCE			ATTY DOCKET NO. SERIAL NO.				
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				APPLICANT				
LIST OF	REFE	RENCES CITED BY APP	PLICANT	Kouji Mitsuhashi, et al.				
				FILING DATE	GROUP			
				November 28, 2003		1763		
			U.S	S. PATENT DOCUMENTS				
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE	
RD	AA	4,842,683	06/1989	Cheng et al.				
	AB	6,663,714	12/203	Mizuno et al.				
	AC	6,726,801	04/2004	Ahn, Jae-Su				
	AD		05-2003	Saito et al.	156	345.24		
	AE	5,885,402	03-1999	Esquibel, James	156	345.24		
	AF	2002/0177001	11-2002	Harada et al.	428	469		
	AG	5,521,790	05-1996	Ruckel et al.	361	234		
	AH	6,068,729	05-2000	Shrotriya, Ashish V.	156	345.26		
	Al	5,968,377	10-1999	Yuasa et al.				
	AJ		09/1999	Yasuda et al.				
	AK		4/2002	Or et al.				
	AL	5,911,852	6/1999	Katayama et al.				
	AM	5,074,456	12/1991	Degner et al.				
	AN	4,612,077	9/1986	Tracy et al.				
	AO	6,182,603	2/2001	Shang et al.				
	AP	2003/0010446	1/2003	Kajiyama et al.				
	AQ	2001/0003271	6/2001	Otsuki				
	AR	2002/0076508	6/2002	Chiang et al.				
	AS	6,368,987	4/2002	Kopacz et al.				
	AT	2004/0072426	4/2004	Jung				
	AU	2005/0150866	07-2005	O'Donnell	216	067	·	
	AV	2003/0113479	06-2003	Fakuda et al.	427	569		
	AW	4,357,387	11-1982	George et al.	442	71		
	AX	5,925,228	07-1999	Panitz	204	484		
	AY	5,892,278	07-1999	Horita .	257	706		
1	AZ	6,073,449	06-2000	Watanabe et al.	62	3.2		
	BA	2005/0103275	02-2004	Sasaki et al.				
•	BB	4,310,390	01-1982	Bradley et al.				
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			U.S	S. PATENT DOCUMENTS		,		
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE	
RD	AA	6,383,964	5/2002	Nakahara et al.				
	AB	6,123,791	9/2000	Han et al.				
	AC	6,170,429	1/2001	Schoepp et al.				
	. AD	6,096,161	8/2000	Kim et al.				
	AE	5,362,335	11/1994	Rungta		ļ		
	AF	5,952,060	9/1999	Ravi				
	AG	5,680,013	10/1997	Domfest et al.				
	АН	5,494,713	2/1996	Ootuki				
	AJ	5,000,113	3/1991	Wang et al.				
	AK	5,334,462	8/1994	Vine et al.				
	AL	6,830,622	12/2004	O'Donnell et al.				
	AM	6,335,293	1/2002	Luo et al.				
	AN	6,221,202	4/2001	Walko, II				
	AO	5,900,064	5/1999	Kholodenko				
	AP	5,641,375	6/1997	Nitescu et al.				
	AQ	6,383,333	5/2002	Haino et al.				
	AR	6,590,660	7/2003	Jung et al.				
	AS	6,570,654	5/2003	Jung et al.				
	AT	6,519,037	2/2003	Jung et al.				
	AU	6,373,573	4/2002	Jung et al.				
	AV	6,246,479	6/2001	Jung et al.				
	AW	5,851,343	12/1998	Hsu et al.				
	AX	6,210,486	4/2001	Mizukami et al.				
	AY	2002/0086118	7/2002	Chang et al.				
	AZ	2003/0029563	2/2003	Kaushal et al.				
	BA		6/1986	Novinski				
	ВВ	5,985,102	11/1999	Leiphart				
	ВС		8/2000	Koai et al.				
	BD		9/2000	Babassi et al.				
	BE	6,265,757	7/2001	Brady et al.				
-1	BF	6,143,646	11/2000	Wetzel		 		
	BG		7/2002	Jiang et al.				
	вн	4,469,619	9/1984	Ohno et al.	1			
	ВІ	5,426,310	6/1995	Tamada et al.	1	1		
	BJ		9/1996	Collins et al.				
	вк		3/1997	Fairbaim et al.		1		
	BL		8/1999	Redeker et al.	_			
	BM	5,994,662	11/1999	Murugesh				
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SHEET 7 OF SERIAL NO. ATTY DOCKET NO. U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE Form PTO 1449 (Modified) 10/722,602 246070US2 APPLICANT LIST OF REFERENCES CITED BY APPLICANT Kouji Mitsuhashi, et al. **GROUP** FILING DATE 1763 November 28, 2003 U.S. PATENT DOCUMENTS **FILING DATE EXAMINER** DOCUMENT SUB CLASS NAME **CLASS** DATE IF APPROPRIATE INITIAL NUMBER 4/1999 Kelsey et al. AA 5,894,887 RD **b**/1999 Tepman et al. AΒ 5,879,575 Ngan et al. 5,759,360 6/1998 AC 8/1998 Oehrlein et al. ΑD 5,798,016 10/2000 Ohashi et al. ΑE 6,139,983 Waku et al. 1/1996 AF 5,484,752 4/1999 Kaji et al. 5,895,586 9/2000 Shih et al. 6,120,640 6,738,862 5/2004 Ross et al. Αi ΑJ 6,783,863 8/2004 Harada et al. 6,837,966 1/2005 Nishimoto et al. ΑK 6,798,519 9/2004 Nishimoto et al. AL AM 2004/0173155 9/2004 Nishimoto et al. AN 6,641,697 11/2003 Han et al. 2004/0081746 4/2004 Imafuku AO 10/2003 Otsuki AΡ 2003/0200929 6,884,516 4/2005 Harada et al. AQ Kanekiyo et al. 6,695,929 2/2004 AR 3/1998 Konishi et al. 5,725,960 AS Yamagishi et al. 9/1996 5,551,190 AT 5/2005 Nishimoto et al. 2005/0103268 ΑIJ 11/2004 Mitsuhashi et al. ΑV 2004/0216667 Additional References sheet(s) attached **Date Considered** Examiner /Rakesh Dhingra/ 08/08/2006 *Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.